

In the United States Patent and Trademark Office

Appn. Number: _____

Appn. Filed: _____

Applicant(s): Liphardt et al

Appn. Title: Sample Markings To Reduce Backside Reflections

Examiner/GAU: _____ 1324

Mailed: With Application

At: _____

Information Disclosure Statement

Commissioner of Patents and Trademarks
Washington, District of Columbia 20231

Sir:

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the references cited thereon.
Following are comments on these references pursuant to Rule 98:

Patent Application No. 2002/0113200 A1 was identified as an aperture 103A is disclosed which can be placed near a detector to block entry of one of two beams from different sources.

Patent No. 3,799,679 to Simko is disclosed as an iris (38) is present near a detector which can be adjusted to block entry of backside reflection thereinto.

Patents to Meeks, Nos. 6,130,749, 6,198,533 and 6,392,749 are disclosed for the presence of a hole 2022 in an integrating sphere near, but not atop a sample.

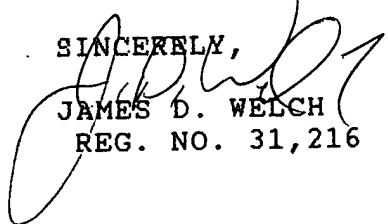
Patent No. 6,088,092 to Chen et al. is disclosed as it applies a spatial filter (28) to block backside reflection entry into a detector.

Patent No. 6,088,104 to Peterson is disclosed as a blocking element (B) is present which can be used to block electromagnetic radiation entry to a detector.

Patent No. 6,097,482 to Smith et al. is disclosed as it applies baffles to block light entry to a detector.

Patent No. 6,166,808 to Greve is disclosed as it describes use of an aperture near a detector to block backside reflections entry to a detector.

SINCERELY,


JAMES D. WELCH
REG. NO. 31,216

Form PTO-1449
REV. 7-01

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

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LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT

Liphardt et al.

FILING DATE

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA	3799679	3/1974	Sinko	358	200	
AB	6130749	10/2000	Meeks et al.	358	381	
AC	6198533	3/2001	Meeks et al.	358	381	
AD	6392749	5/2002	Meeks et al.	358	387	
AE	6088092	7/2000	Chen et al.	358	237.2	
AF	6088104	7/2000	Peterson	358	371	
AG	6097482	8/2000	Smith et al.	358	237.1	
AH	6166808	12/2000	Greve	358	375	
AI						
AJ						
AK						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AL							
AM							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AR	<i>US 2002/0113200 A1, Published Application of Hajjar et al. 8/22/02</i>					
AS						

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.